

**ROCHESTER INSTITUTE OF TECHNOLOGY
MICROELECTRONIC ENGINEERING**

BJT Characterization Laboratory

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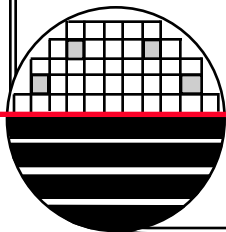
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MicroE Webpage: <http://www.microe.rit.edu>



OUTLINE

2N3904

BE Junction

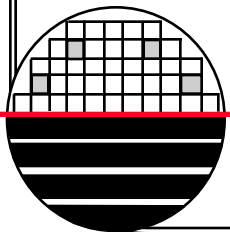
BC Junction

IC-VCE Family of Curves

Beta at low, medium, high currents

SPICE Models

Temperature Effects



DEFINITIONS

Bipolar Junction Transistor - (BJT) Both holes and electrons participate in the conduction of current, hence the name bipolar.

Minority carrier - In a p-type semiconductor electrons are the minority carrier type, in an n-type semiconductor holes are the minority carrier type.

Emitter - Emits minority carriers into the base region of a BJT. For example, in an NPN BJT the n-type emitter, emits electrons into the p-type base. The emitter usually has the highest doping levels of the three regions of a BJT.

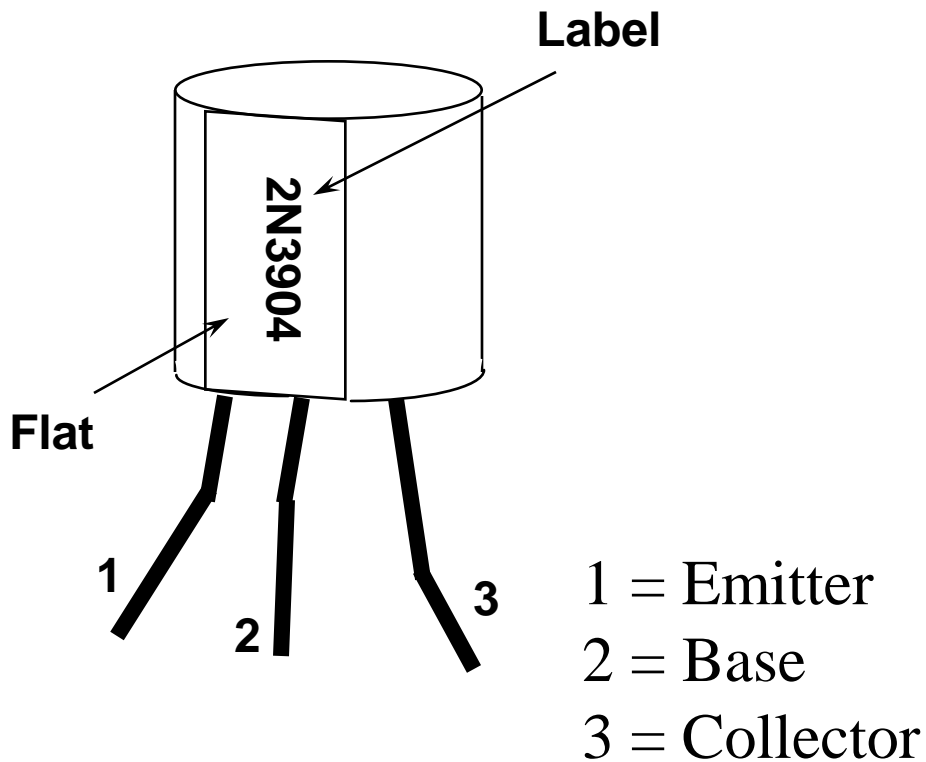
Base - Thin region which is used to control the flow of minority carriers from the emitter to the collector

Collector -Collects the minority carriers that make it through the base from the emitter. The collector usually has the lightest doping concentrations of the three regions.

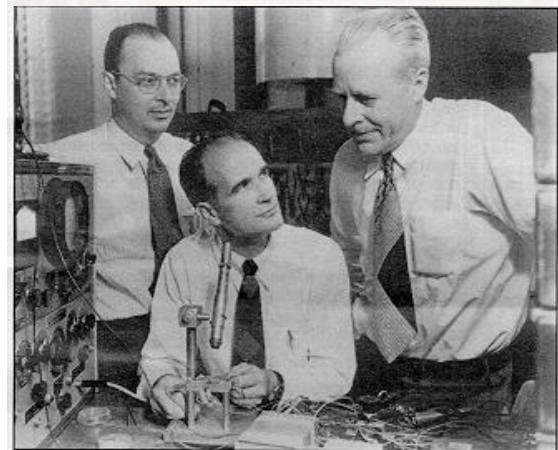
DC Beta (β_{dc}) - The ratio of the collector current to the base current. $\beta_{dc} = I_C / I_B$

AC Beta (β_{ac}) - The ratio of the change in the collector current to the change in the base current. $\beta_{ac} = \Delta I_C / \Delta I_B$

BJT - BIPOLAR JUNCTION TRANSISTOR



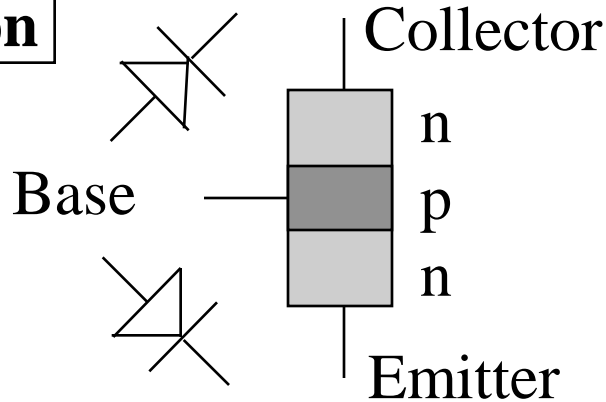
The world's first transistor, built at Bell Labs in December, 1947.



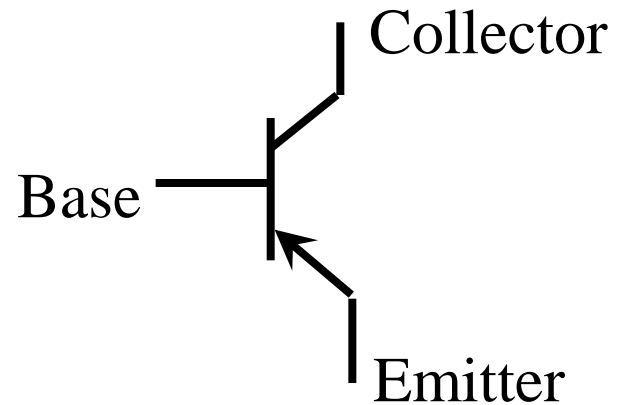
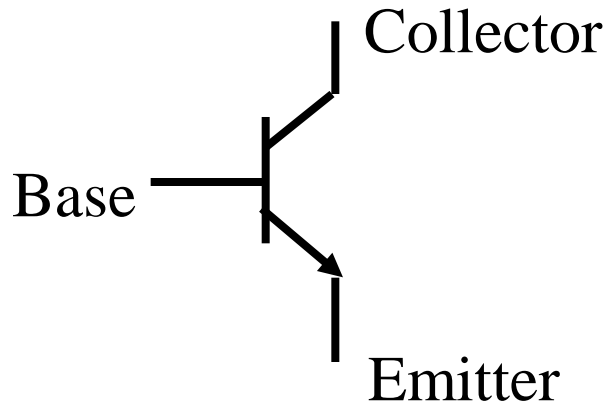
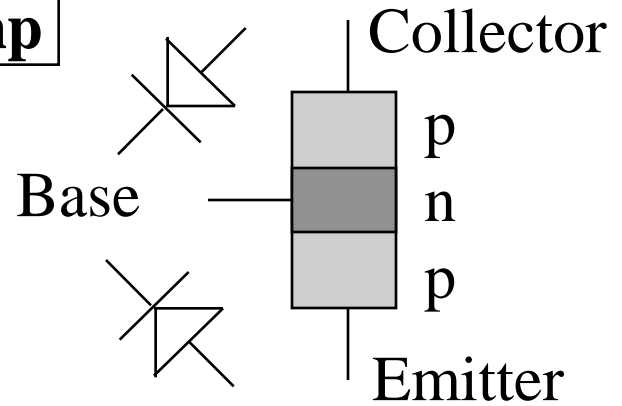
Transistor inventors (from left), Dr. Walter Brattain, Dr. William Shockley, and Dr. John Bardeen.

SCHEMATIC SYMBOLS

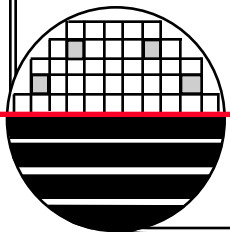
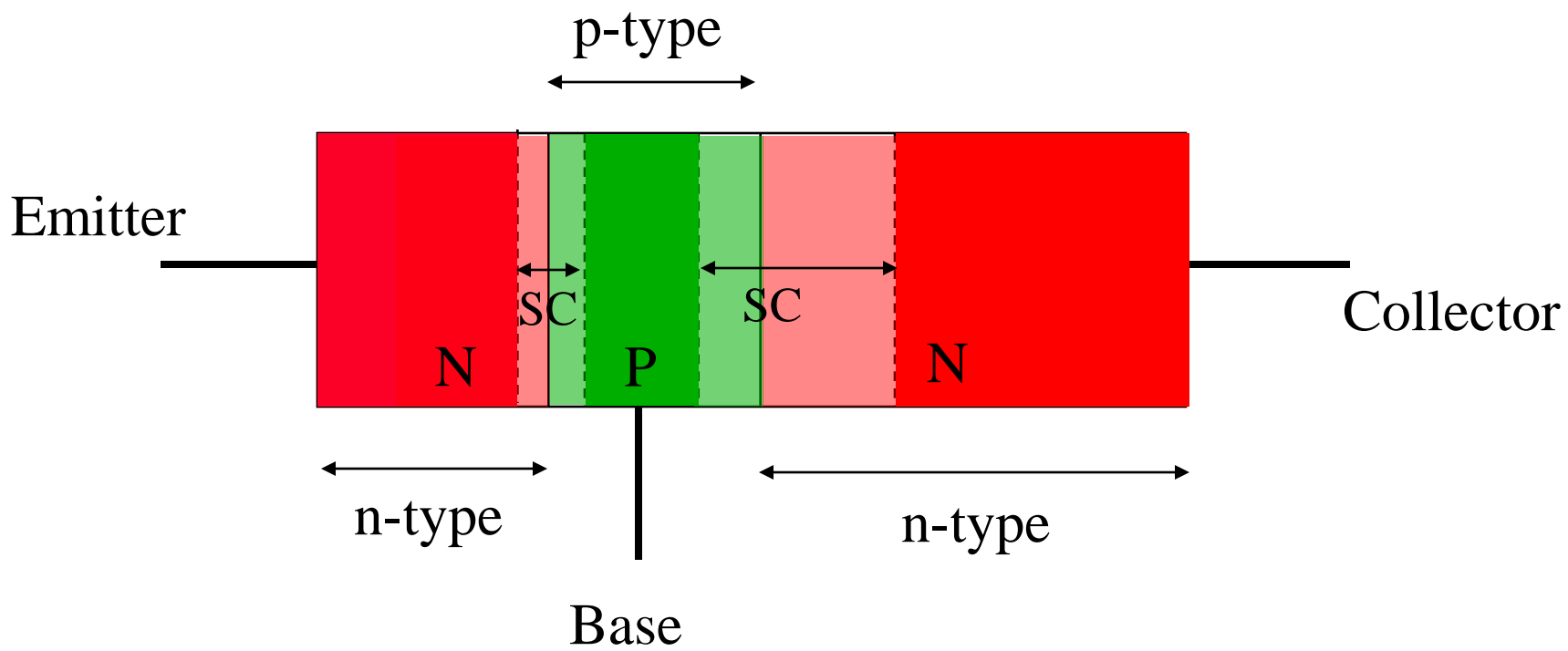
npn



pnp



IDEALIZED STRUCTURE



ELECTRON CONCENTRATIONS IN AN NPN BJT

Emitter

Base

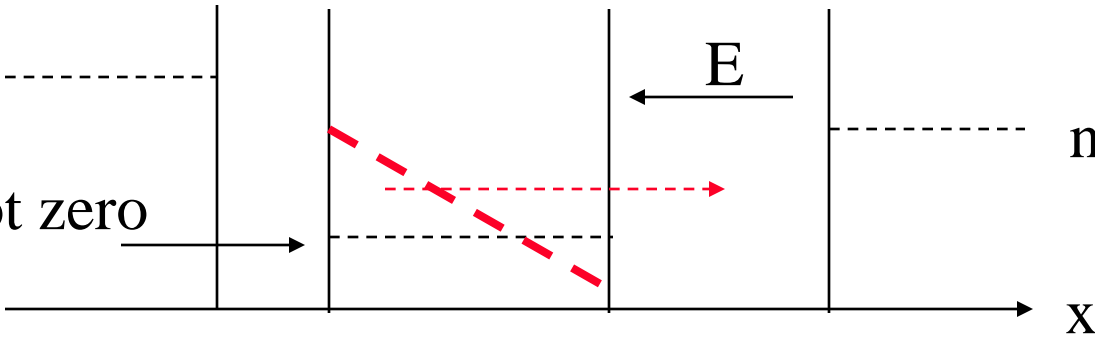
Collector

$n \sim N_{de}$

E

$n \sim N_{dc}$

$n \sim$ very small but not zero
 $\sim n_i^2 / N_{ab}$



BE

BC

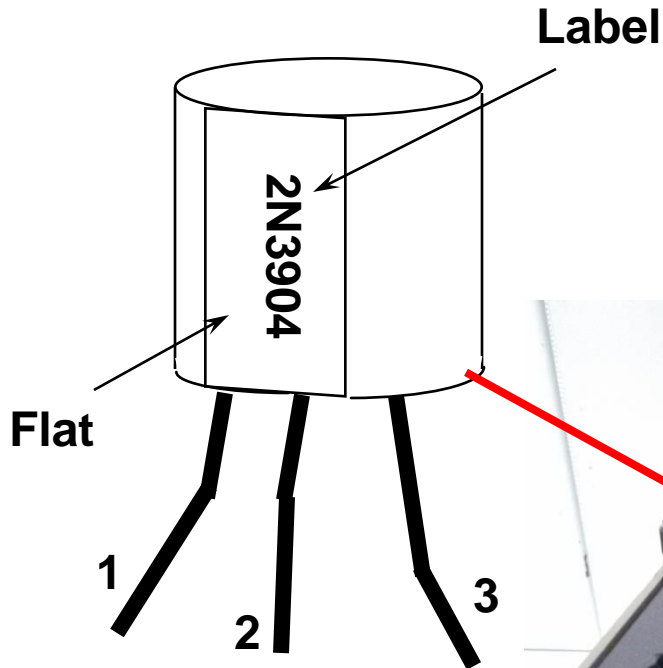
Space Charge Layer

With the B-E junction forward biased, and B-C junction reverse biased. There is a concentration gradient in the base that forces electrons to flow toward the collector.

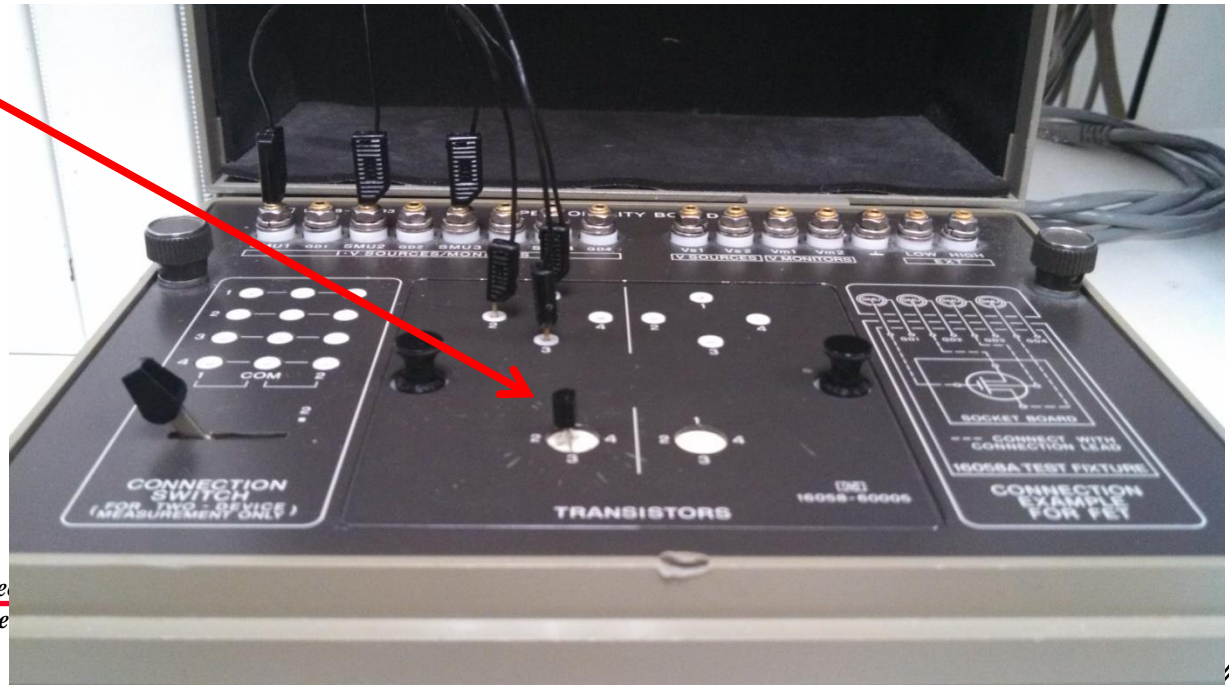
COMMENTS

1. The concentration of electrons in n-type silicon is \sim doping concentration in that region.
2. In p-type silicon the number of electrons is almost zero
3. A forward biased pn junction means more carriers of both types can cross the potential barrier. So a forward biased base-emitter junction (in an npn BJT) means more electrons on the base side than in equilibrium (no bias).
4. A reverse biased pn junction means less carriers of both types can cross the potential barrier. So a reverse biased base-collector junction (in an npn BJT) means less electrons on the base side than in equilibrium (no bias). Even closer to zero electrons in p-type base at the edge of the B-C space charge layer.
5. The base is so narrow that few electrons are lost as they diffuse across the base width. Diffusion is driven by a concentration gradient. So electrons move towards the collector and current flows in the opposite direction.

2N3904



Test Fixture

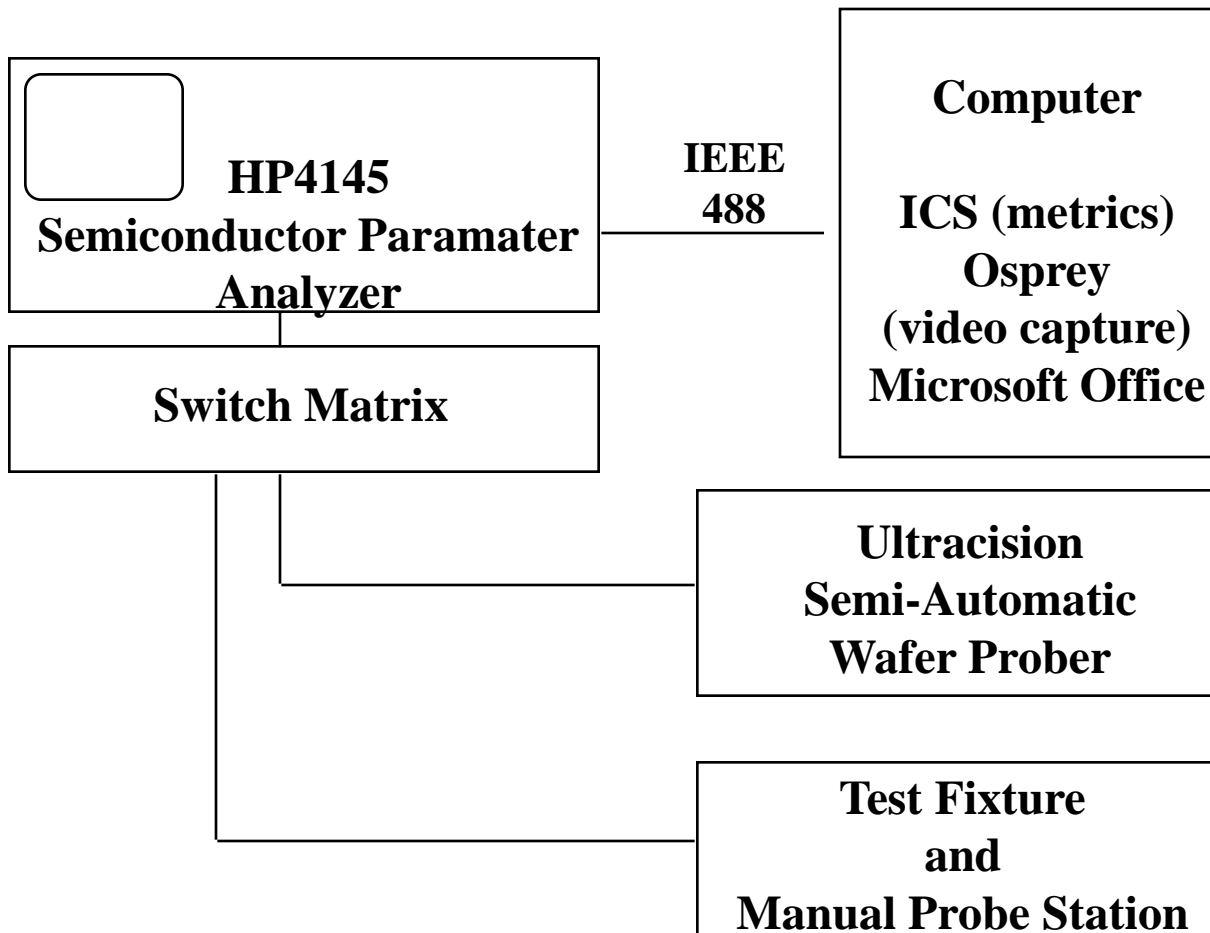


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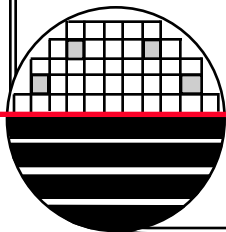
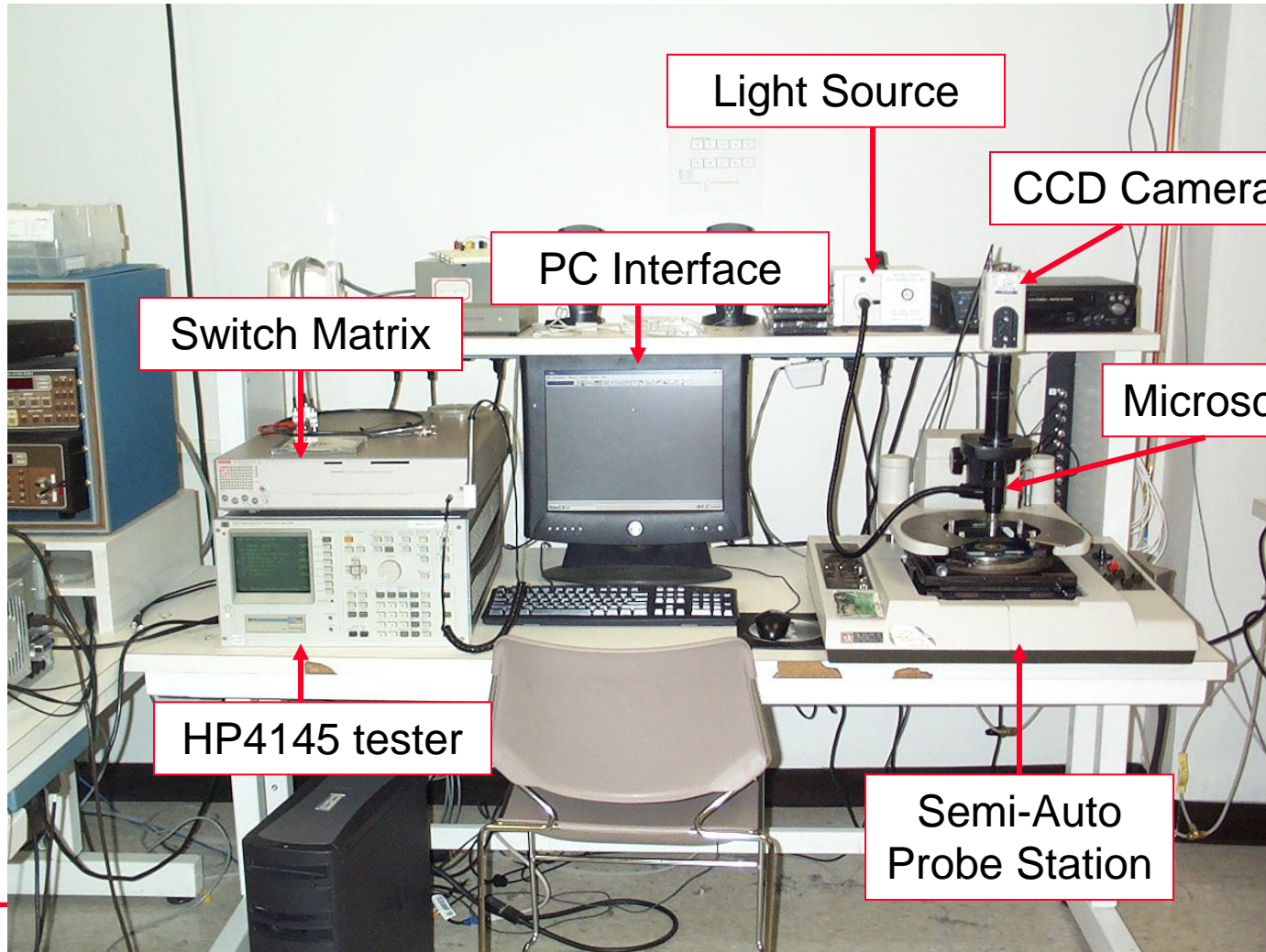
HP4145B SEMICONDUCTOR PARAMETER ANALYZER



TEST EQUIPMENT



TEST STATION



OPERATION OF HP4145 AND SWITCH MATRIX

Turn on the HP4145, Switch Matrix, and PC

Select ICS icon on the desktop (close and message window)

Click on GPIB icon on the top of the screen select NI-32Thunk

Click on Instrument icon and select HP4145

Click on device icon and select PN Diode or BJT

Click on SMU1 then click on terminal (n-side of diode)
set SMU1 to zero volts ground

Click on SMU2 then click on terminal (p-side of diode)
set SMU2 to sweep from -10 to 10 Volts, measure
I and V

Click on done

Click on measure button

Wait for data to graph then add cursors, lines, titles, source conditions

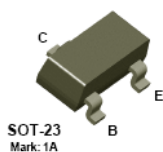
2N3904 DATA SHEET

FAIRCHILD
SEMICONDUCTOR™

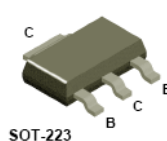
2N3904



MMBT3904



PZT3904



NPN General Purpose Amplifier

This device is designed as a general purpose amplifier and switch. The useful dynamic range extends to 100 mA as a switch and to 100 MHz as an amplifier.

Absolute Maximum Ratings* T_A = 25°C unless otherwise noted

Symbol	Parameter	Value	Units
V _{CEO}	Collector-Emitter Voltage	40	V
V _{CBO}	Collector-Base Voltage	60	V
V _{EB0}	Emitter-Base Voltage	6.0	V
I _C	Collector Current - Continuous	200	mA
T _J , T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

*These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

- 1) These ratings are based on a maximum junction temperature of 150 degrees C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics T_A = 25°C unless otherwise noted

Symbol	Characteristic	Max			Units
		2N3904	*MMBT3904	**PZT3904	
P _D	Total Device Dissipation Derate above 25°C	625 5.0	350 2.8	1,000 8.0	mW mW/°C
R _{θJC}	Thermal Resistance, Junction to Case	83.3			°C/W
R _{θJA}	Thermal Resistance, Junction to Ambient	200	357	125	°C/W

* Device mounted on FR-4 PCB 1.6" X 1.6" X 0.06"

** Device mounted on FR-4 PCB 36 mm X 18 mm X 1.5 mm; mounting pad for the collector lead min. 6 cm².

2N3904 / MMBT3904 / PZT3904

NPN General Purpose Amplifier

(continued)

Electrical Characteristics T_A = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHARACTERISTICS					
V _{BR(CEO)}	Collector-Emitter Breakdown Voltage	I _C = 1.0 mA, I _B = 0	40		V
V _{BR(CBO)}	Collector-Base Breakdown Voltage	I _C = 10 μA, I _E = 0	60		V
V _{BR(EB0)}	Emitter-Base Breakdown Voltage	I _E = 10 μA, I _C = 0	6.0		V
I _{BL}	Base Cutoff Current	V _{CE} = 30 V, V _{EB} = 3V		50	nA
I _{CEX}	Collector Cutoff Current	V _{CE} = 30 V, V _{EB} = 3V		50	nA

ON CHARACTERISTICS*

h _{FE}	DC Current Gain	I _C = 0.1 mA, V _{CE} = 1.0 V	40		
		I _C = 1.0 mA, V _{CE} = 1.0 V	70		
		I _C = 10 mA, V _{CE} = 1.0 V	100	300	
		I _C = 50 mA, V _{CE} = 1.0 V	60		
		I _C = 100 mA, V _{CE} = 1.0 V	30		
V _{CE(sat)}	Collector-Emitter Saturation Voltage	I _C = 10 mA, I _B = 1.0 mA I _C = 50 mA, I _B = 5.0 mA		0.2 0.3	V
V _{BE(sat)}	Base-Emitter Saturation Voltage	I _C = 10 mA, I _B = 1.0 mA I _C = 50 mA, I _B = 5.0 mA	0.65	0.85 0.95	V

SMALL SIGNAL CHARACTERISTICS

f _T	Current Gain - Bandwidth Product	I _C = 10 mA, V _{CE} = 20 V, f = 100 MHz	300		MHz
C _{ob0}	Output Capacitance	V _{CB} = 5.0 V, I _E = 0, f = 1.0 MHz		4.0	pF
C _{ib0}	Input Capacitance	V _{EB} = 0.5 V, I _C = 0, f = 1.0 MHz		8.0	pF
NF	Noise Figure	I _C = 100 μA, V _{CE} = 5.0 V, R _θ = 1.0kΩ, f = 10 Hz to 15.7kHz		5.0	dB

SWITCHING CHARACTERISTICS

t _d	Delay Time	V _{CC} = 3.0 V, V _{BE} = 0.5 V, I _C = 10 mA, I _{B1} = 1.0 mA		35	ns
t _r	Rise Time	V _{CC} = 3.0 V, I _C = 10mA		200	ns
t _f	Fall Time	I _{B1} = I _{B2} = 1.0 mA		50	ns

* Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%

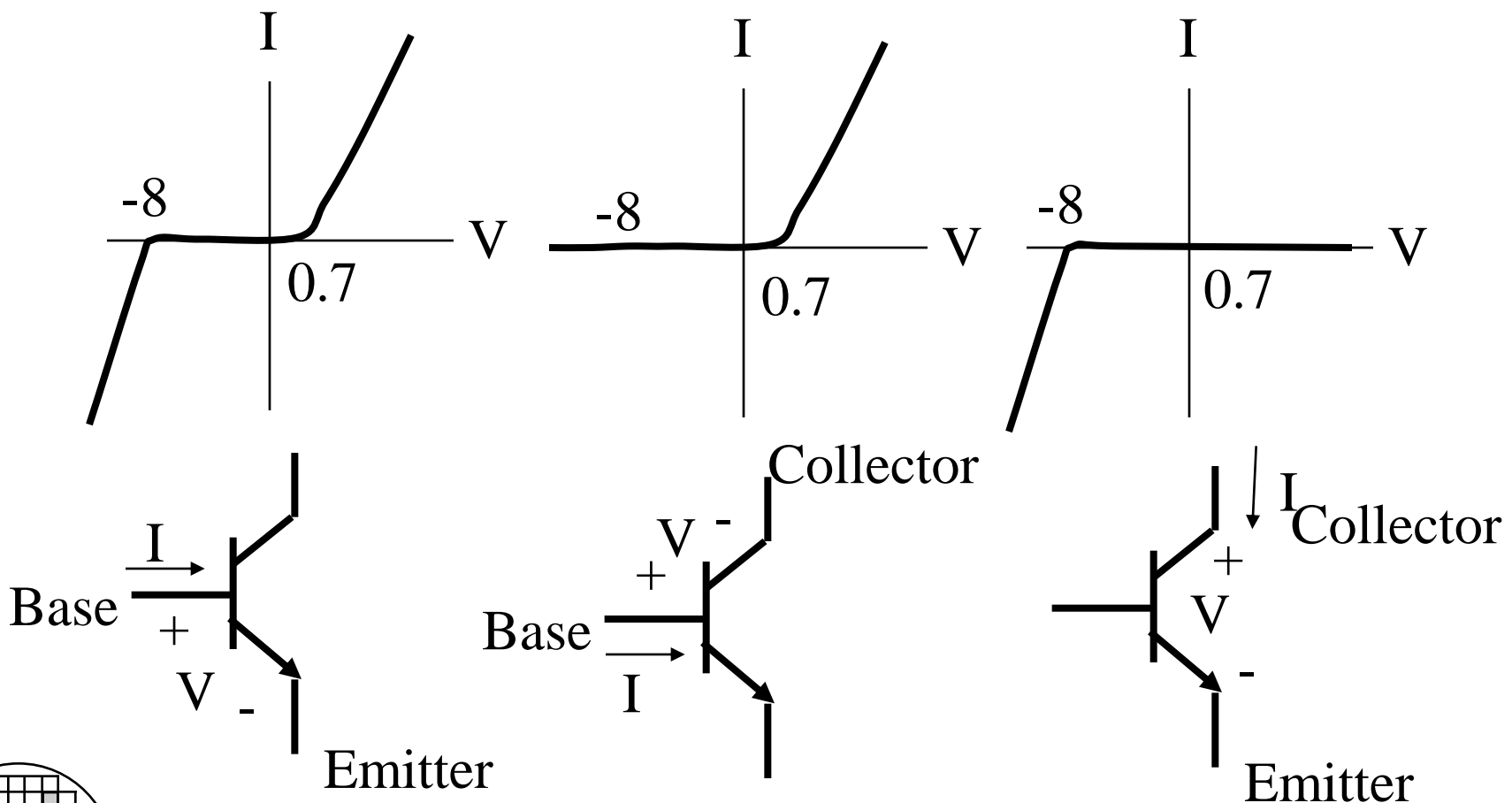
Spice Model

NPN (Is=6.734f XtI=3 Eg=1.11 Vaf=74.03 Bf=416.4 Ne=1.259 Ise=6.734 If=66.78m Xtb=1.5 Br=7371 Nc=2 Isc=0 Ikr=0 Rc=1 Cjc=3.638p Mjc=.3085 Vjc=.75 Fc=.5 Cje=4.493p Mje=.2593 Vje=.75 Tr=239.5n Tf=301.2p IfI=4 Vlf=4 Xti=2 Rb=10)

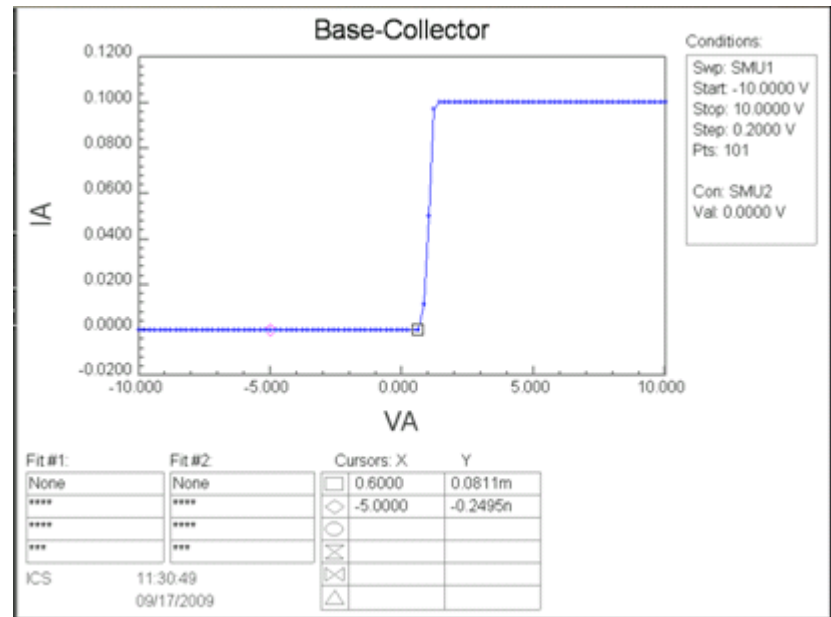
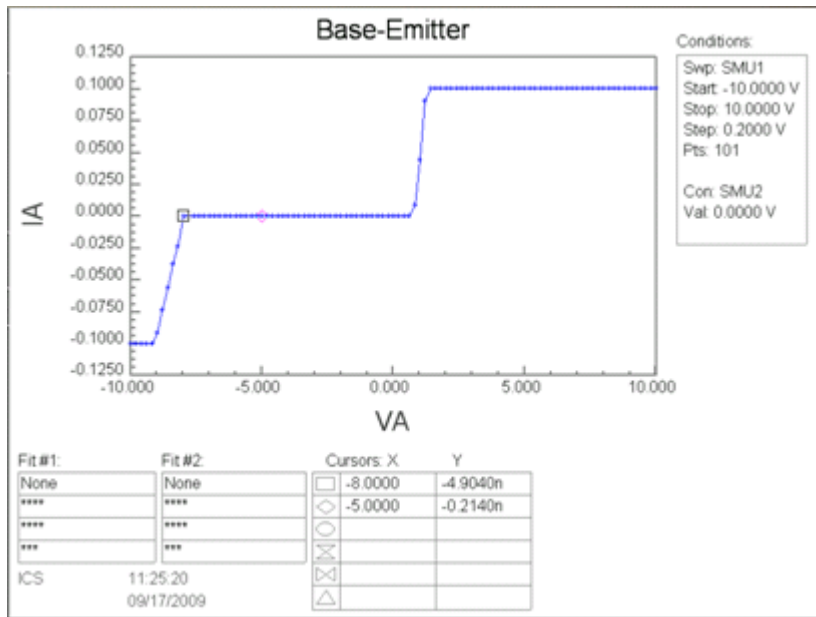
2N3904 / MMBT3904 / PZT3904

Note: see page 12-15 of this document for more information on BJT SPICE parameters

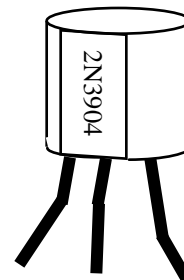
THEORETICAL BE JUNCTION, BC JUNCTION, CE



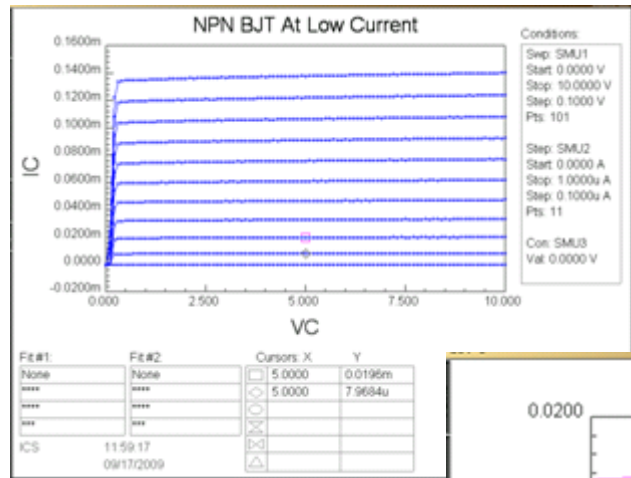
BE AND BC DIODE CHARACTERISTICS



Identify BE junction, measure ISE and VBE. Identify BC junction and measure IS. Identify Base, Emitter, Collector leads and label on sketch.



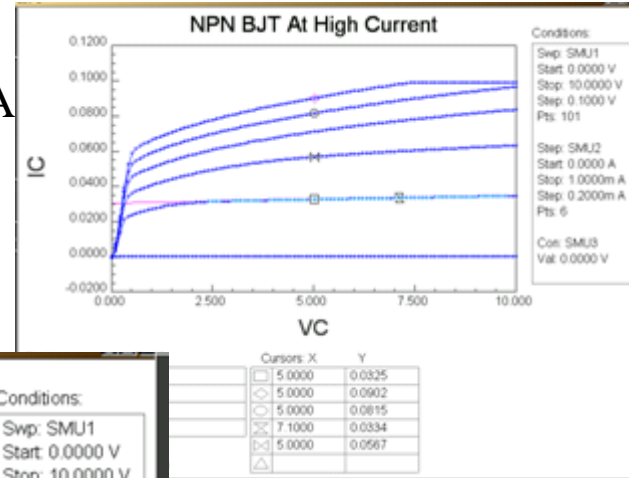
BETA MEASURED FROM FAMILY OF CURVES



Beta = 116 @
~0.02mA and Vce=5

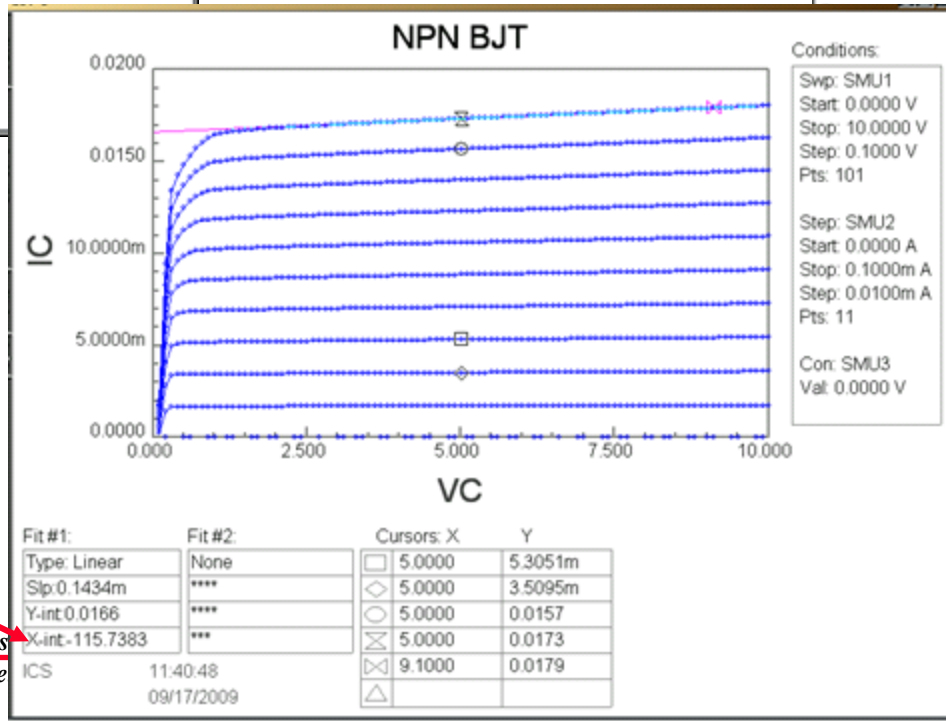
Early Voltage is measured to be 116 for IC ~ 15 mA

Beta = 44 @ ~90mA
and Vce=5



Beta = 121 @
~40mA and Vce=5

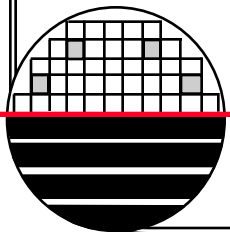
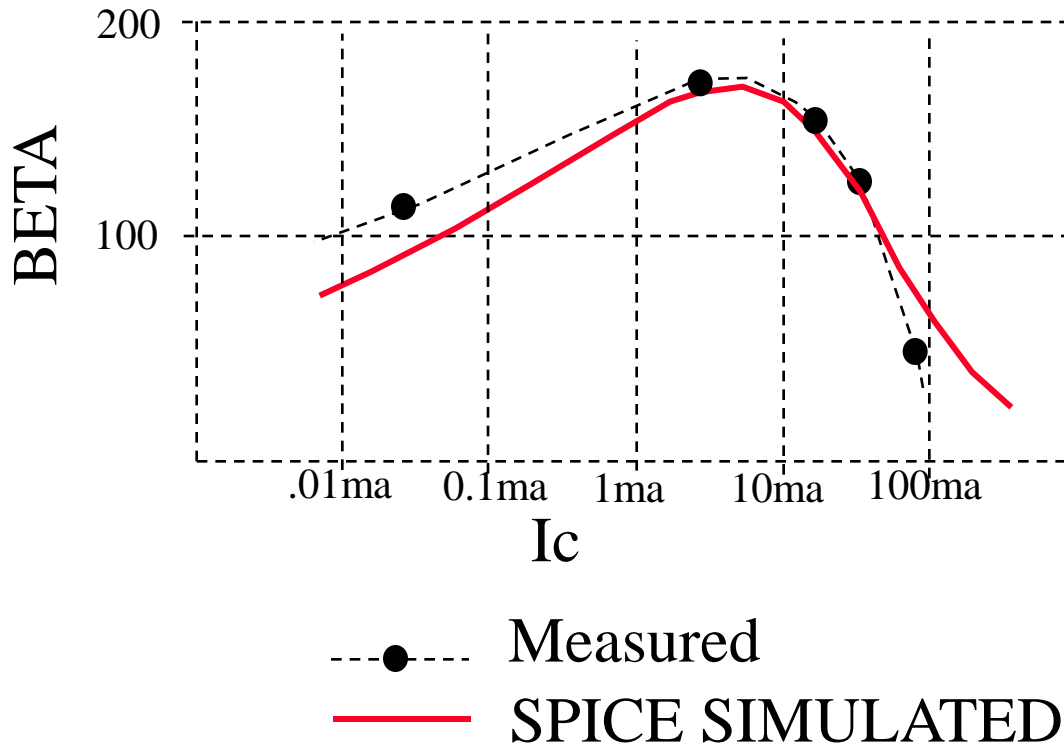
Beta = 160 @
~15mA and Vce=5



Beta = 180 @ ~5mA
and Vce=5

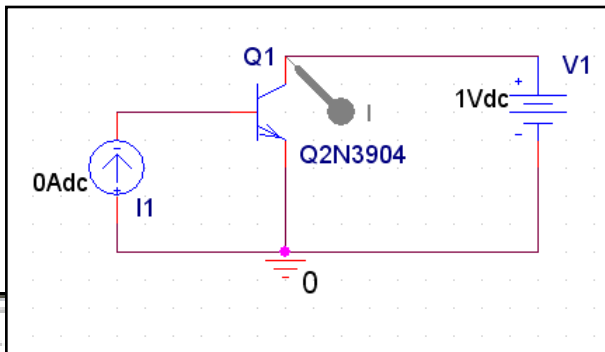
Roches
Microe

BETA VS IC – 2N3904



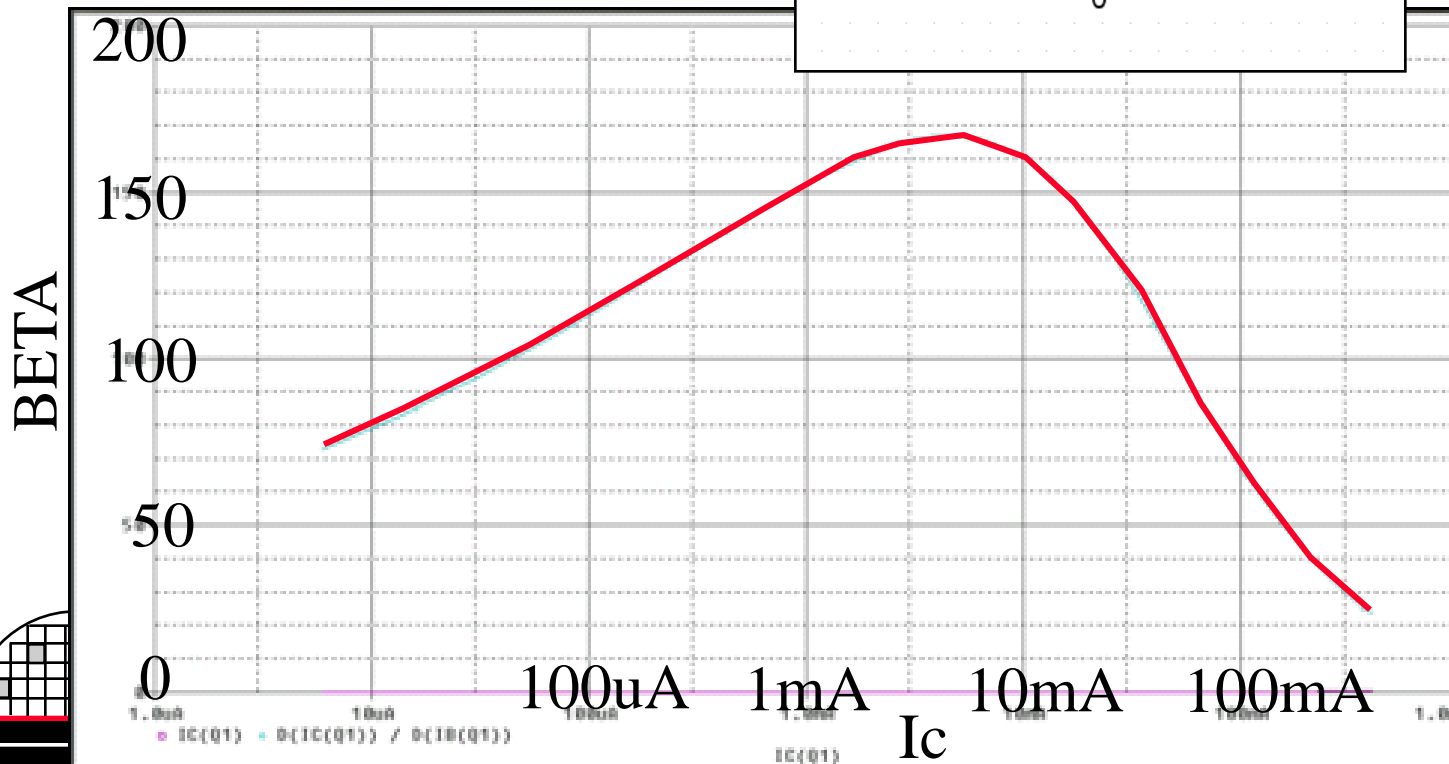
SPICE SIMULATED

SPICE Simulatin of
Beta vs Ic



SPICE Model

	Q2N3904
	NPN
IS	6.734000E-15
BF	416.4
NR	1
VAF	74.03
IKF	.06678
ISE	6.734000E-15
NE	1.259
BR	.7371
NR	1
RB	10
RC	1
CJE	4.493000E-12
MJE	.2593
CJC	3.638000E-12
MJC	.3085
TF	301.200000E-12
XTF	2
VTF	4
ITF	.4
TR	239.500000E-09
XTB	1.5
CN	2.42
D	.87



2N3904 SPICE MODEL

From the datasheet above

Spice Model

NPN (Is=6.734f Xti=3 Eg=1.11 Vaf=74.03 **Bf=416.4** Ne=1.259 Ise=6.734 Ikf=66.78m Xtb=1.5 Br=.7371 Nc=2
 Isc=0 Ikr=0 Rc=1 Cjc=3.638p Mjc=.3085 Vjc=.75 Fc=.5 Cje=4.493p Mje=.2593 Vje=.75 Tr=239.5n Tf=301.2p
 Itf=.4 Vtf=4 Xtf=2 Rb=10)

h_{FE}	DC Current Gain	$I_C = 0.1 \text{ mA}, V_{CE} = 1.0 \text{ V}$	40	300
		$I_C = 1.0 \text{ mA}, V_{CE} = 1.0 \text{ V}$	70	
		$I_C = 10 \text{ mA}, V_{CE} = 1.0 \text{ V}$	100	
		$I_C = 50 \text{ mA}, V_{CE} = 1.0 \text{ V}$	60	
		$I_C = 100 \text{ mA}, V_{CE} = 1.0 \text{ V}$	30	

Why does the SPICE model have Bf of 416 when the maximum Bf=300

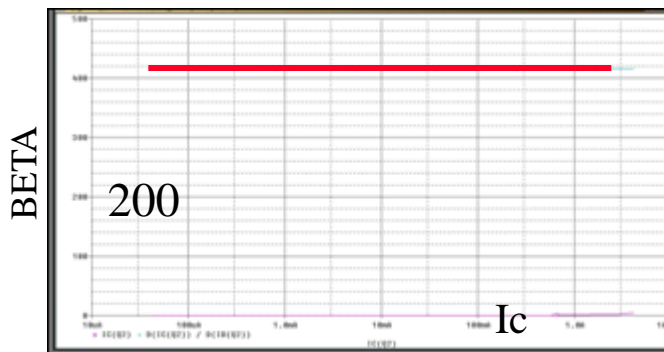
Answer: It is a model parameter and when combined with other model parameters give correct results. See next page.

BJT SPICE PARAMETERS EFFECT ON BETA

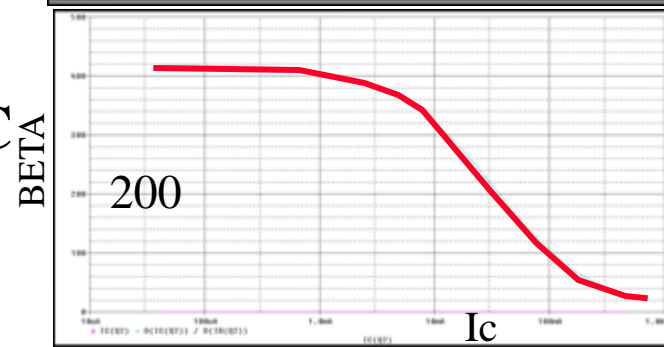
When BF=419 is used by itself it gives incorrect results

Adding IKF to the model helps reduce BF at high IC

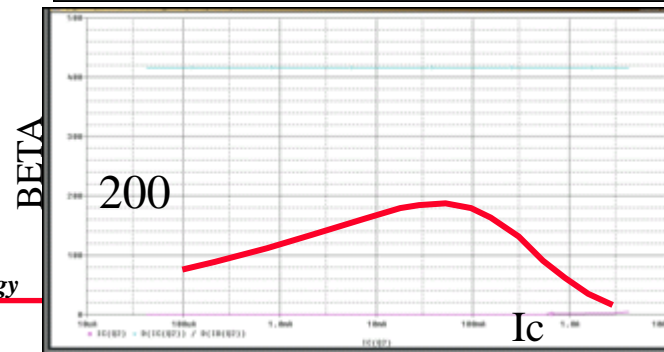
Adding IS, ISE and NE makes the model give correct results for all IC



QTRITNPN
NPN
BF 416

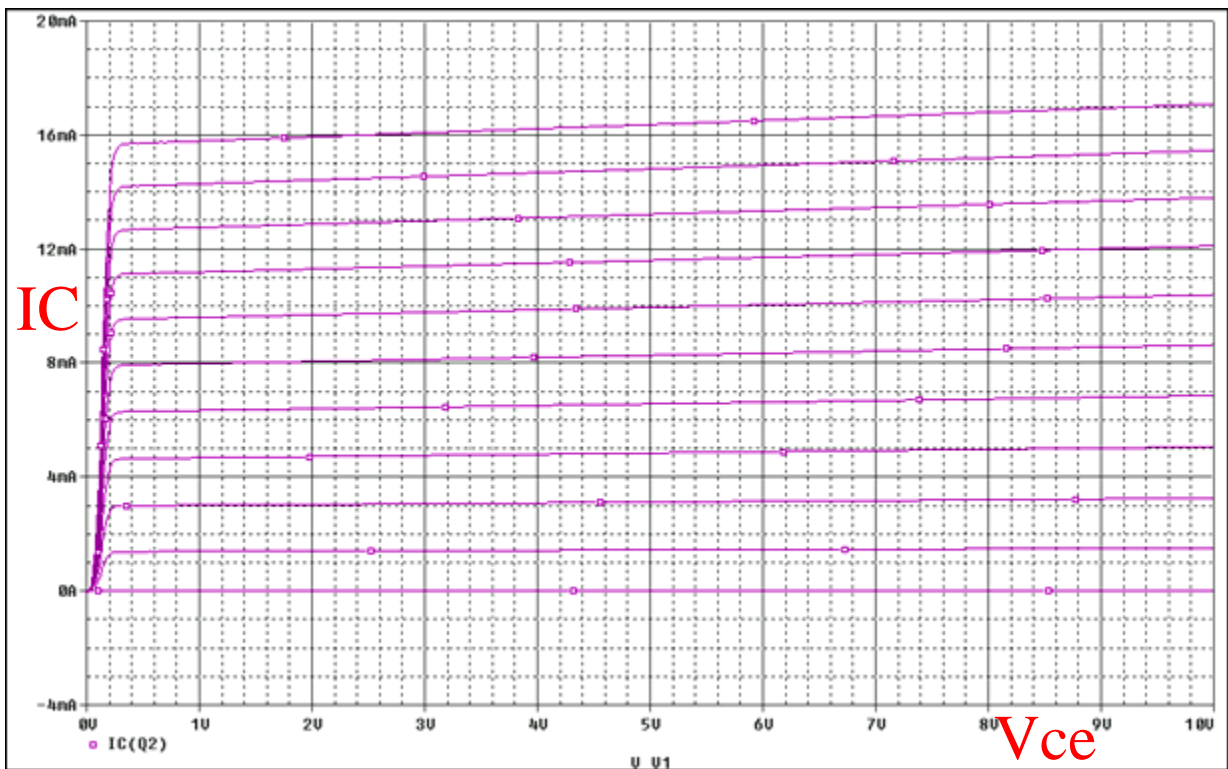


QTRITNPN
NPN
BF 416
IKF .06678



QTRITNPN
NPN
BF 416
IKF .06678
IS 6.734000E-15
ISE 6.734000E-15
NE 1.259

IC=VCD FAMILY OF CURVES

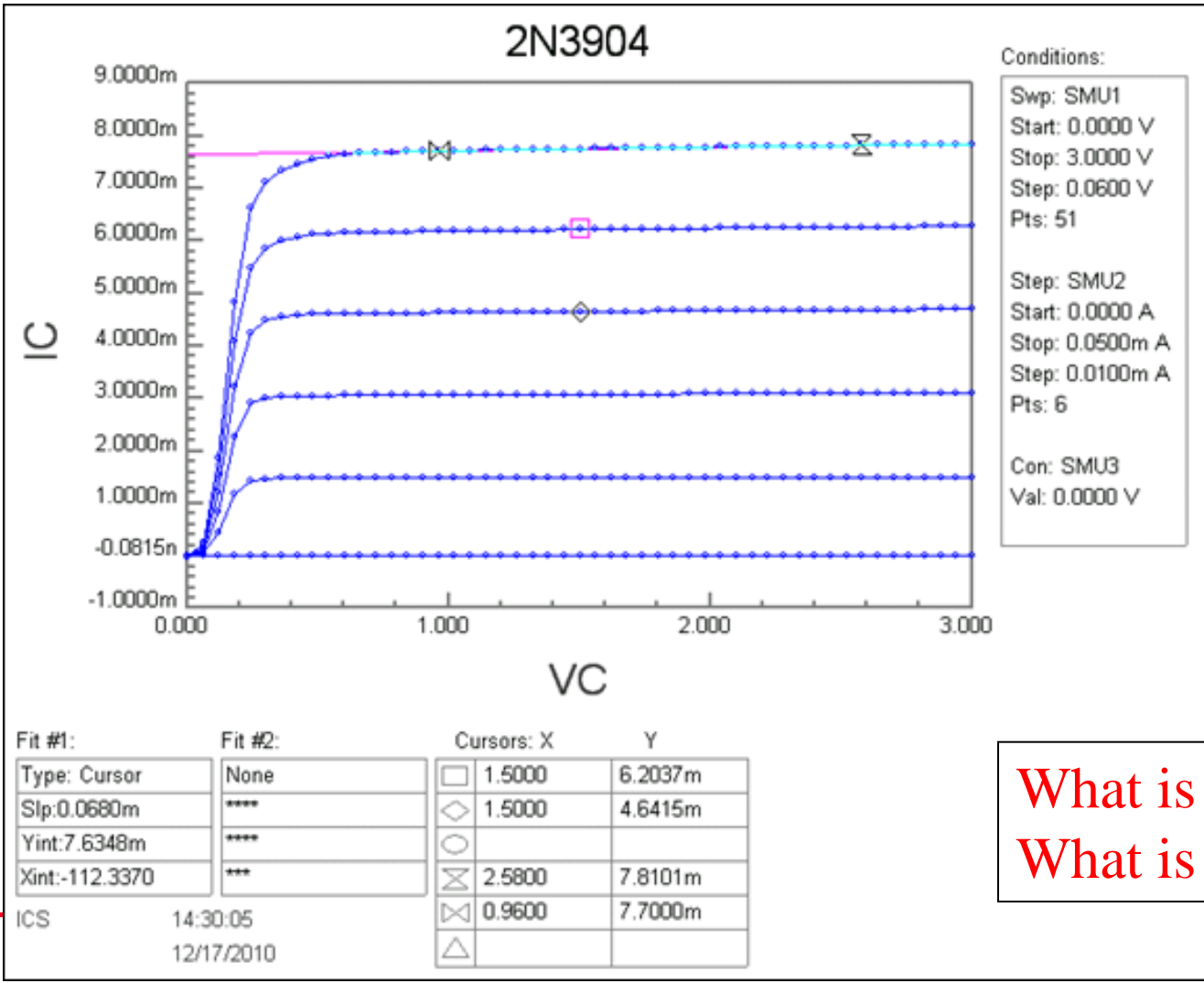


SPICE MODEL

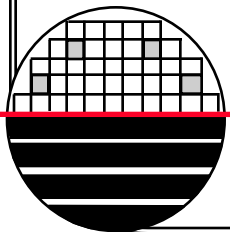
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QRITNPN
NPN
IS 6.734000E-15
BF 416
IKF .06678
ISE 6.734000E-15
NE 1.259
RB 10
RC 1
VA 109
```

SPICE SIMULATION

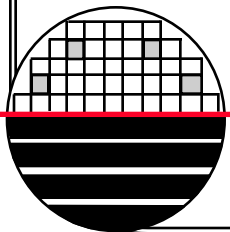
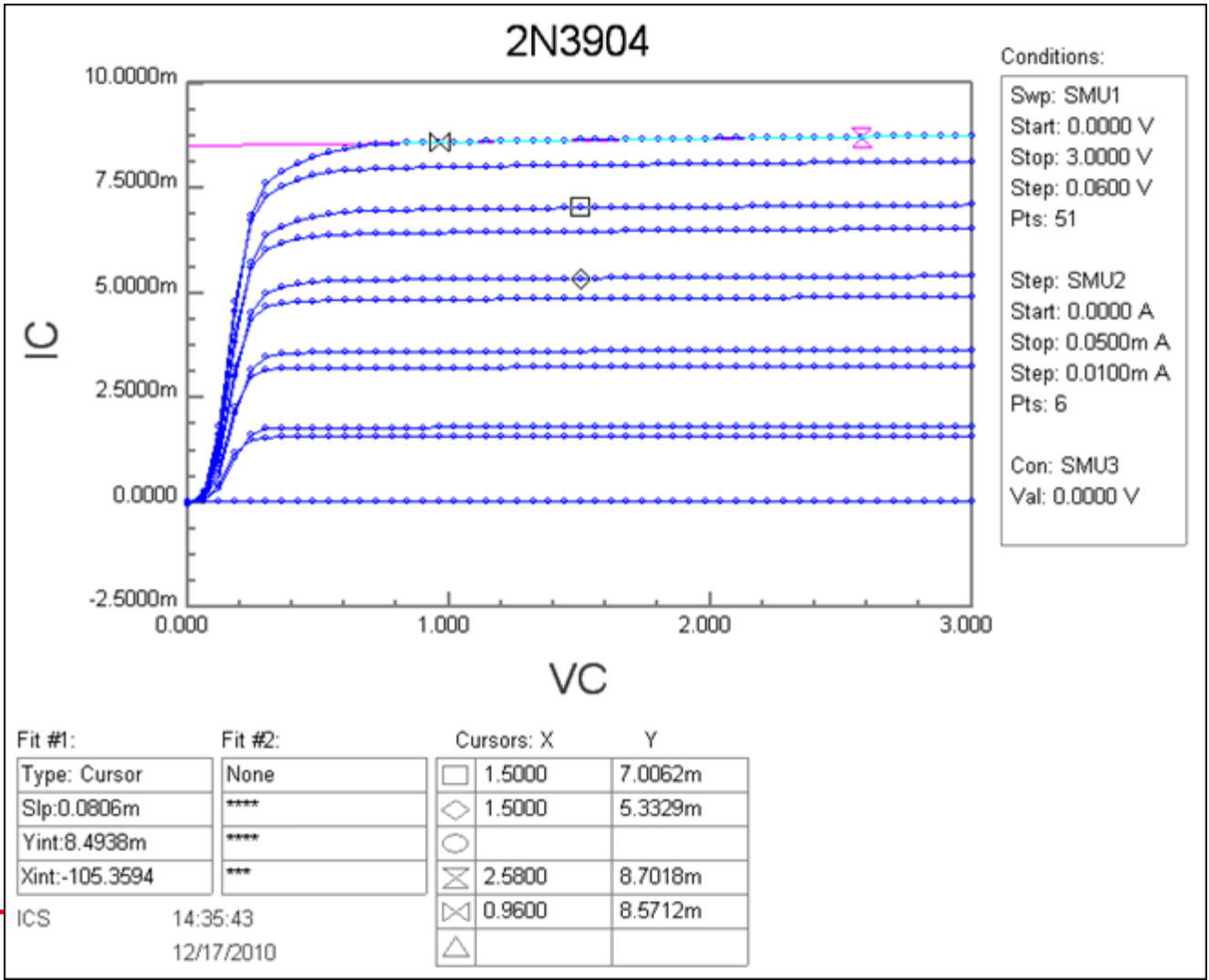
2N3904 FORWARD ACTIVE



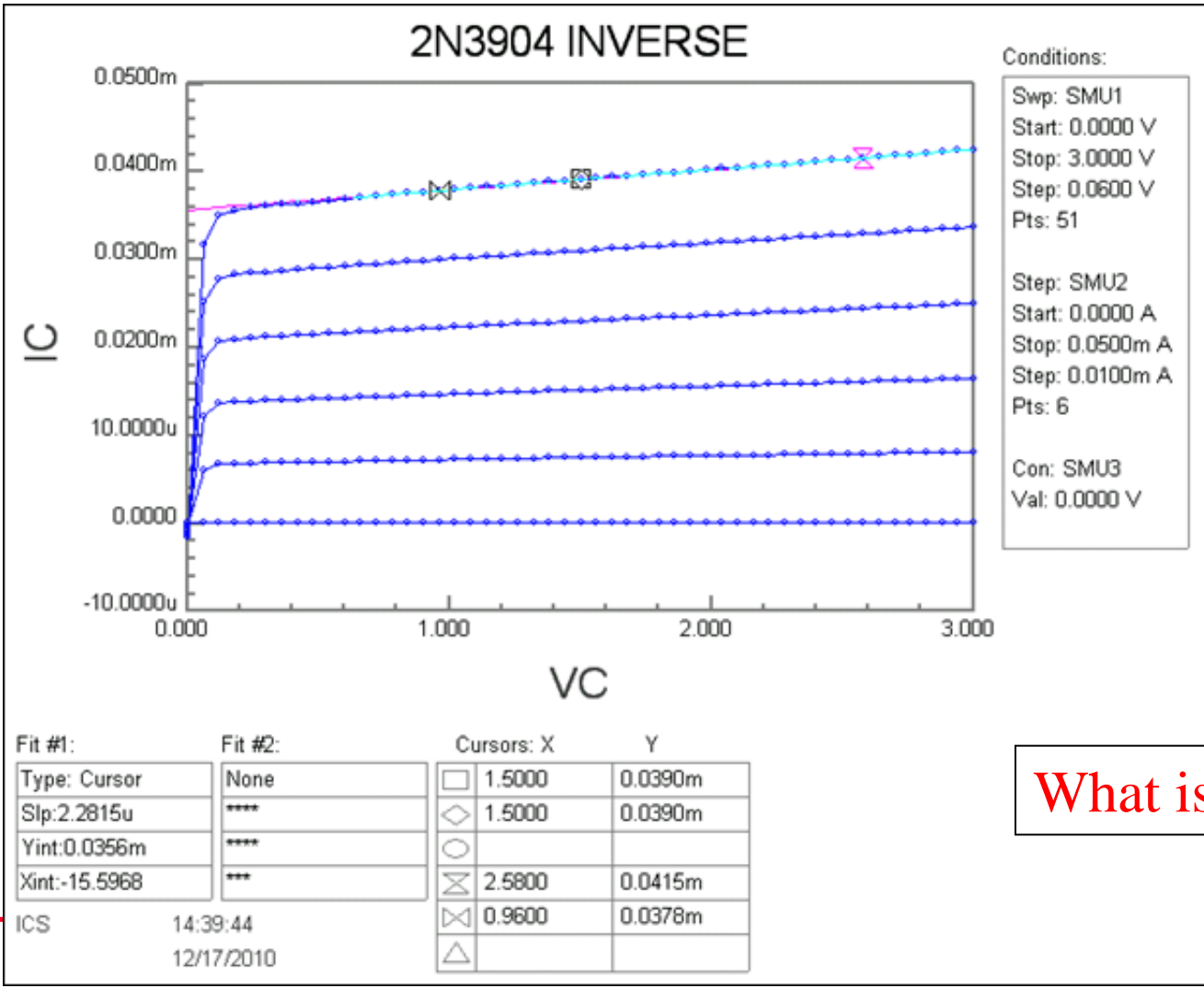
What is Beta?
What is VA?



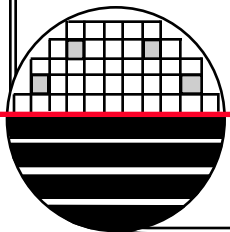
TEMPERATURE EFFECT ON FAMILY OF CURVES



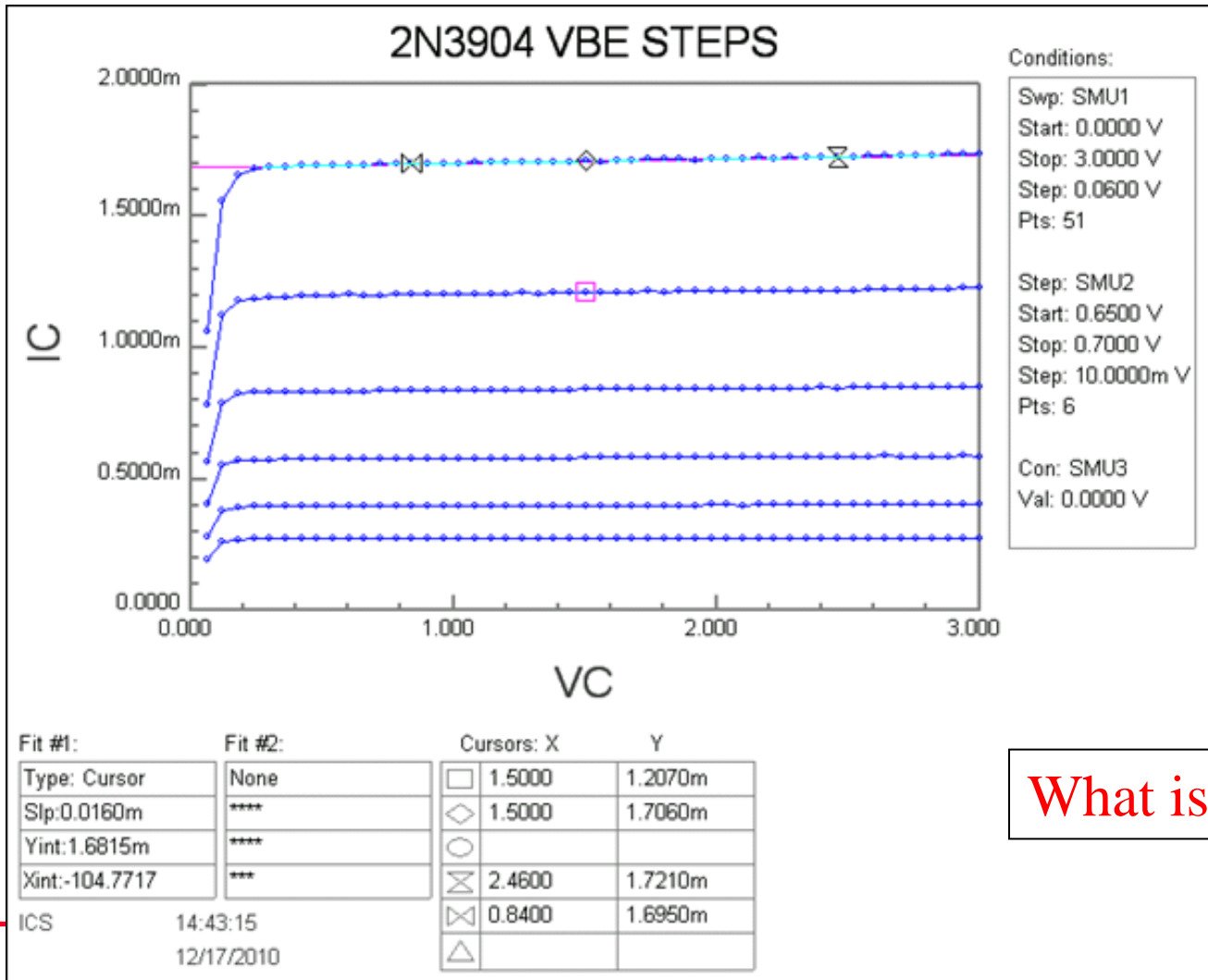
2N3904 INVERSE MODE



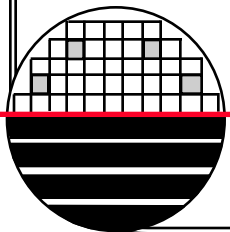
What is Beta?



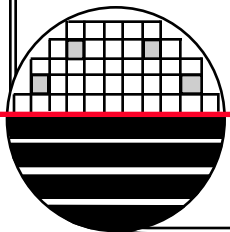
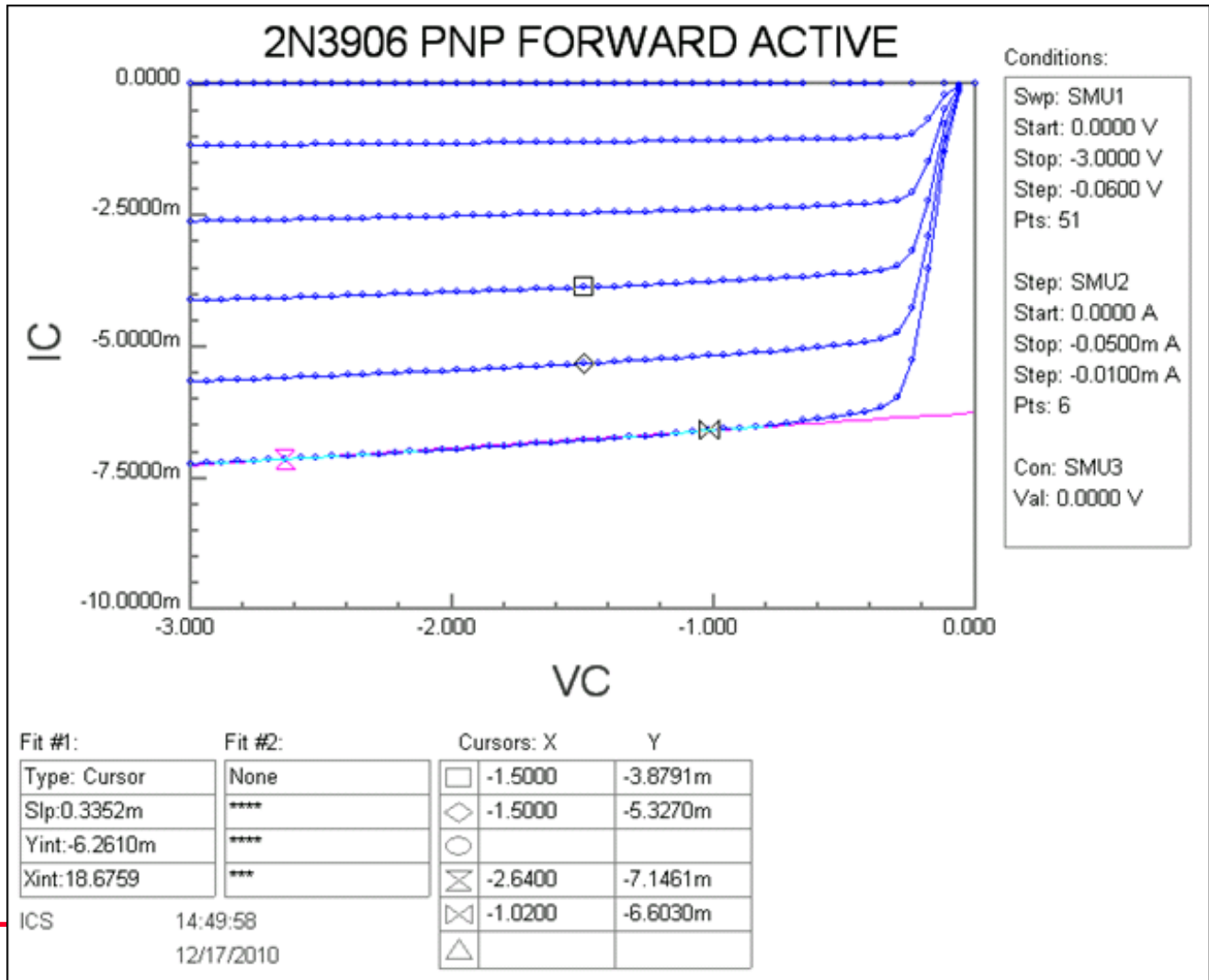
2N3904 VBE STEPS



What is gm?

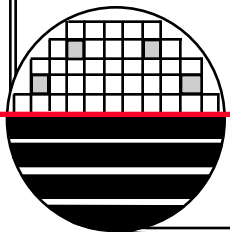


PNP FORWARD ACTIVE



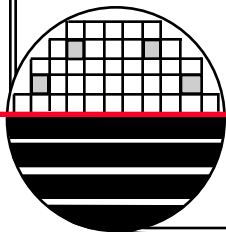
REFERENCES

1. MOSFET Modeling with SPICE, Daniel Foty, 1997, Prentice Hall, ISBN-0-13-227935-5
2. Operation and Modeling of the MOS Transistor, 2nd Edition, Yannis Tsividis, 1999, McGraw-Hill, ISBN-0-07-065523-5
3. UTMOST III Modeling Manual-Vol.1. Ch. 5. From Silvaco International.
4. ATHENA USERS Manual, From Silvaco International.
5. ATLAS USERS Manual, From Silvaco International.
6. Device Electronics for Integrated Circuits, Richard Muller and Theodore Kamins, with Mansun Chan, 3rd Edition, John Wiley, 2003, ISBN 0-471-59398-2
7. ICCAP Manual, Hewlet Packard
8. PSpice Users Guide.



LAB WORK USING HP4145

- Obtain I-V plot for BE junction
 - Obtain I-V plot for BC junction
 - Obtain I-V plot for C-E
 - Obtain I_c - V_{ce} family of curves for 2n3904 (for different I_b 's)
 - Extract V_A Early Voltage
 - Extract Beta at 5 different I_C values (0.1mA to 100mA)
 - Obtain I_c - V_{ce} family of curves at elevated temperature
 - Obtain I_c - V_{ce} family of curves for inverse operation
 - Extract Beta Inverse
 - Obtain I_c - V_{ce} curves for different V_{be}
- Repeat some or all of above for 2N3906



HOMWORK – BJT CHARACTERIZATION

Use SPICE to obtain the following:

1. I_c - V_{ce} family of curves for 2N3904
2. Extract V_A Early Voltage
3. Extract Beta at 5 different I_C values (0.1mA to 100mA)
4. Obtain I_c - V_{ce} family of curves at elevated temperature
5. Obtain I_c - V_{ce} family of curves for inverse operation
6. Extract Beta Inverse
7. Obtain I_c - V_{ce} curves for different V_{be}

